

<b>Notice of References Cited</b>	Application/Control No. 10/017,355		Applicant(s)/Patent Under Reexamination SPITZ ET AL.	
	Examiner BINH K. TIEU		Art Unit 2614	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2002/0128908	09-2002	Levin et al.	705/14
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	M	US-			

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**NON-PATENT DOCUMENTS**

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